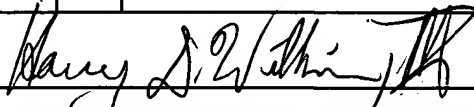
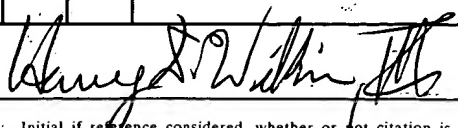
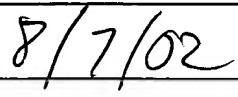


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5004 DIV3		PRIORITY SERIAL NO. 09/465,492		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal et al.				
				PRIORITY FILING DATE December 16, 1999		PRIORITY GROUP 1742		
U.S. PATENT DOCUMENTS								
*Examiner Initial	Class	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	4,619,695	10/1986	Oikawa et al.	75	65EB		
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HW	AC	5,513,512	05/1996	Segal	72	253.1		
HW	AD	5,590,389	12/1996	Dunlop et al.	419	67		
HW	AE	5,600,989	02/1997	Segal et al.	72	253.1		
HW	AF	5,673,581	10/1997	Setal	72	184		
HW	AG	4,663,120	05/1987	Parent et al.				
HW	AH	4,762,558	08/1988	German et al.				
HW	AI	4,889,745	12/1989	Sata				
HW	AJ	5,330,701	07/1994	Shaw et al.				
HW	AK	5,418,071	05/1995	Satou et al.				
HW	AL	5,508,000	04/1996	Satou et al.				
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		Document Number	Date	Country	Class	Subclass	Translation	
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HW	AM	590904	04/1994	EP	C23C	14/34		
HW	AN	9201080	01/1992	PCT	C23C	14/35		
HW	AO	610107	01/1994	Japan (*transl. of Abst)	C22	18	X*	
HW	AP	693400	04/1994	Japan (*transl. of Abst)	C22	18	X*	
HW	AQ	6256919	09/1994	Japan (*transl. of Abst)	C22	18	X*	
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
HW	AR		C. Klein et al., "Manual of Mineralogy", pp 39-40					
HW	AS		S. Wright et al. "Effect of Annealing Temperature on the Texture of Rolled Tantalum and Tantalum-10 Wt.% Tungsten, reprinted from Tungsten and Refractory Metals 2, pp 501-508					
HW	AT		H-R Wenk, "Preferred Orientation in Deformed Metals and Rocks: An Introduction to Modern Texture Analysis", 1985, pp 8-10					
EXAMINER					DATE CONSIDERED			8/7/02
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

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U.S. PATENT DOCUMENTS							
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AW	AC	5,993,621	11/1999	Liu			
AW	AD	5,798,005	08/1998	Murata et al.			
AW	AE	5,282,946	02/1994	Kinoshita et al.			
AW	AF	5,993,575	11/1999	Lo et al.			
AW	AG	5,809,393	04/1998	Dunlop et al.			
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AW	AI	5,087,297	02/1992	Pouliquen			
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AW	AL	4,525,417	06/1985	Dimigen et al.			
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	Document Number	Date	Country	Class	Subclass	Translation	
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AW	AM	8-100255	04/1996	Japan			X
AW	AN	8-64554	03/1996	Japan			X
AW	AO	06264232	09/1994	Japan			X
AW	AP	WO 00/31310	06/2000	PCT			
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AW	AR	B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297					
	AS						
	AT						
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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HW	AB	4,842,706	06/1989	Fukasawa et al.				
HW	AC	4,960,163	10/1990	Fang et al.				
HW	AD	5,780,755	07/1998	Dunlop et al.				
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	AG							
	AH							
	AI							
	AI							
	AK							
	AC							
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HW	AM	08269701	10/1996	Japan			X	
HW	AN	08232061	06/1996	Japan			X	
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
HW	AR		B.D. Cullity, "Structure of Polycrystalline Aggregates", <u>Elements of X-ray Diffraction</u> , pp 294-297					
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EXAMINER		<i>Henry D. Wilkin</i>			DATE CONSIDERED <i>8/7/02</i>			
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal			
				FILING DATE July 24, 2001			

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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	5,850,755	12/98	Segal			
HW	AB	5,456,815	10/95	Fukuyo et al.			
HW	AC	5,826,456	10/98	Kawazoe et al.			
HW	AD	5,413,650	5/95	Jarrett et al.			
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HW	AG	6,085,966	7/00	Shimomuki et al.			
HW	AH	6,024,852	2/00	Tamura et al.			
HW	AI	5,798,005	08/98	Murata et al.			
HW	AJ	5,231,306	07/93	Meikle et al.			
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	AL						

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					Yes	No	
HW	AM	WO 99/66100	23.12.1999	PCT			
HW	AN	WO 87/07650	17.12.1987	PCT			
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HW	AP	08146201	07.06.1996	Japan			
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HW	AT		Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.

EXAMINER	DATE CONSIDERED
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal	
				FILING DATE July 24, 2001	GROUP 1734 1742

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FOREIGN PATENT DOCUMENTS								
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HW	AN	WO 99/02743	21.01.1999	PCT				
HW	AO	WO 01/29279 A1	26.04.2001	PCT				
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HW	AR		Pavate et al., "Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect-density", SPIE Vol. 3214, 1997, pp. 42-47.
HW	AS		Hatch, J.E., <u>ALUMINUM</u> , 1984, Chap. 5, "Metallurgy of Heat Treatment and General Principles of Precipitation Heating", pp. 134-157, 175-183.
	AT		

EXAMINER <i>Henry S. Wilkins</i>	DATE CONSIDERED <i>8/7/02</i>
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